

Form 1449 (Modified)

Information Disclosure
Statement By Applicant

Atty Docket No. INT 899C1
 Application No.: 09/09,053
 Inventor BAKER, et al
 Group 2612
 Filing Date January 12, 2001

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JUL 09 2002
PATENT & TRADEMARK OFFICE

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-Class	Filing Date
LN	A	3,946,696	3/76	Lubnow	114	221R	
	B	4,418,993	12/6/83	Lipton			5/7/81
	C	4,717,958	1/98	Gal et al	348	208	
	D	5,004,328	4/2/91	Masayuki et al			9/25/87
	E	5,049,988	9/17/91	Sefton, et al			8/10/89
	F	5,063,441	11/5/91	Lipton et al			10/11/90
	G	5,142,357	8/25/92	Lipton et al			5/9/91
	H	5,206,503	4/27/93	Toops			8/7/91
	I	5,270,861	12/93	Estelle	359	676	
	J	5,402,171	3/28/95	Tagami, et al			9/10/93
	K	5,440,343	8/95	Parulski et al	348	316	
	L	5,453,784	9/95	Krishnan et al	348	348	
	M	5,453,785	9/26/95	Lenhardt et al	348	357	7/28/93
	N	5,548,327	8/96	Tagami et al	348	219	
	O	5,712,483	1/98	Boone et al	250	367	
	P	5,721,608	2/98	Taniguchi	355	53	RECEIVED
	Q	5,812,191	9/98	Orava et al	348	308	JUL 23 2002
LN	R	5,819,120	10/98	Hamada et al	386	77	

Technology Center 2600

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-Class	Translation
							Yes No
LN	S	GB2210530A	6/7/89	UK			
LN	T	EP0512403A	11/11/92	EPO			X
LN	U	DE4304529C	6/30/94	Germany			X
LN	V	JP07303207A	11/14/95	Japan			X
	W	05288532	11/2/93	Japan			

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	X	Isabella T. Lewis, "WFOV Star Tracker Camera," June 1991, SPIE Vol. 1478, OCI Applied Optics, Garden Grove, CA pp. 2-12.
	Y	Hye-Sook Park et al., "Realtime Tracking System for the Wide-Field-of-View Telescope Project," 1989, Lawrence Livermore National Laboratory, SPEI Vol. 1111, pp. 196-203.
	Z	National Defense Research Committee, Optical Research Laboratory-Harvard Univ., Spherically Symmetrical Lenses and Associated Equipment for Wide Angle Aerial Photography, Contract No. OEMsr-474, 6/6/46.
Examiner	Date Considered 8/14/04	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form 1449 (Modified)		Docket No. INT1P004A	Application No. 08/989,202
Information Disclosure Statement By Applicant		Applicant: Baker et al.	
(Use Several Sheets if Necessary)		Filing Date 12/12/97	Group 2612

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U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
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B							
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Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
L								
M								
N								
O								
P								

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	R	National Defense Research Committee, Optical Research Laboratory Harvard University, <i>Spherically Symmetrical Lenses and Associated Equipment for Wide Angle Aerial Photography</i> , Contract No. OEMsr 474, June 6, 1946
Examiner		Date Considered 8/4/04

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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Information Disclosure Statement By Applicant		Application No.: 09/759,053
		Inventor BAKER, et al
		Group 2612
		Filing Date January 12, 2001
(Use Several Sheets if Necessary)		

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LN	B	6,204,880	3/2001	Nishimura	348	240.99	_____
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G							
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I							
J							Technology Center 2600
K							

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Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
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N								
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P								

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication		
	R			
	S			
	T			
Examiner	Leorahuna Naveen	Date Considered	8/4/04	

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